



**ALPHA & OMEGA**  
SEMICONDUCTOR



## AOTF470

### N-Channel Enhancement Mode Field Effect Transistor

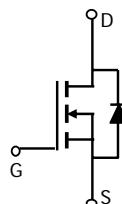
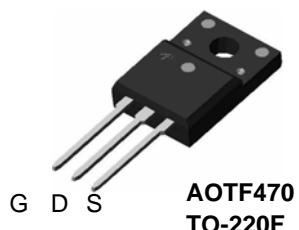
#### General Description

The AOTF470 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

-RoHS Compliant

#### Features

$V_{DS}$  (V) = 75V  
 $I_D$  = 50 A ( $V_{GS}$  = 10V)  
 $R_{DS(ON)}$  < 11.5m $\Omega$  ( $V_{GS}$  = 10V)



#### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	AOTF470	Units
Drain-Source Voltage	$V_{DS}$	75	V
Gate-Source Voltage	$V_{GS}$	$\pm 25$	V
Continuous Drain Current <sup>A</sup>	$T_C=25^\circ\text{C}$	50	A
$T_C=100^\circ\text{C}$	$I_D$	36	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	200	
Avalanche Current <sup>C</sup>	$I_{AR}$	45	A
Repetitive avalanche energy $L=0.3\text{mH}$ <sup>C</sup>	$E_{AR}$	300	mJ
Power Dissipation <sup>B</sup>	$T_C=25^\circ\text{C}$	54	W
$T_C=100^\circ\text{C}$	$P_D$	27	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 175	°C

#### Thermal Characteristics

Parameter	Symbol	AOTF470	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	60	°C/W
Maximum Junction-to-Case <sup>B</sup>	$R_{\theta JC}$	2.8	°C/W

**AOTF470**
**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	75			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=60\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 25\text{V}$			1	$\text{uA}$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2	2.7	4	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	200			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=30\text{A}$		9.8	11.5	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		16.0	19.0	
$g_{\text{FS}}$	Transconductance	$V_{DS}=5\text{V}, I_D=50\text{A}$		90		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
$I_S$	Maximum Body-Diode Continuous Current				20	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=30\text{V}, f=1\text{MHz}$		4700	5640	pF
$C_{\text{oss}}$	Output Capacitance			400		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			180		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		3	4.5	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, I_D=30\text{A}$		114	140	nC
$Q_{\text{gs}}$	Gate Source Charge			33		nC
$Q_{\text{gd}}$	Gate Drain Charge			18		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, R_L=1\Omega, R_{\text{GEN}}=3\Omega$		21		ns
$t_r$	Turn-On Rise Time			39		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			70		ns
$t_f$	Turn-Off Fall Time			24		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=30\text{A}, dI/dt=100\text{A}/\mu\text{s}$		53	70	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=30\text{A}, dI/dt=100\text{A}/\mu\text{s}$		143		nC

A: The value of  $R_{\theta JA}$  is measured with the device in a still air environment with  $T_A=25^\circ\text{C}$ .

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=175^\circ\text{C}$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300\ \mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=175^\circ\text{C}$ .

G. The maximum current rating is limited by bond-wires.

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### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

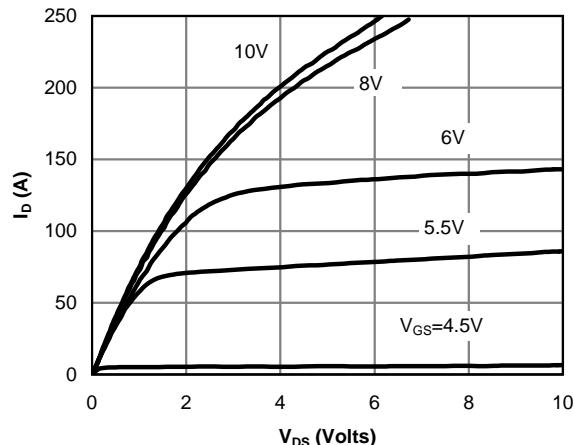


Figure 1: On-Region Characteristics

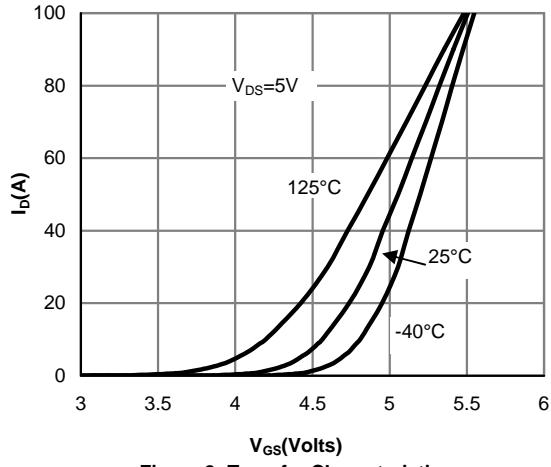


Figure 2: Transfer Characteristics

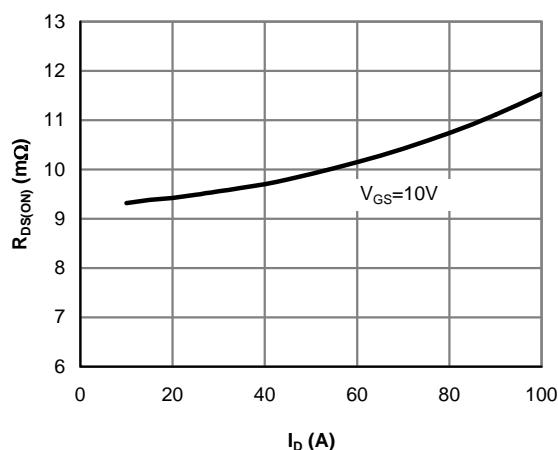


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

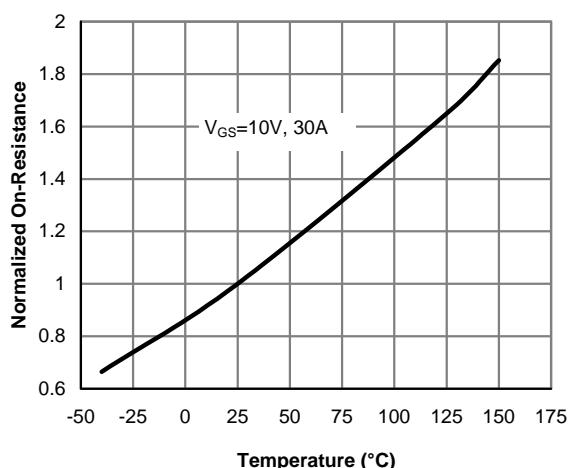


Figure 4: On-Resistance vs. Junction Temperature

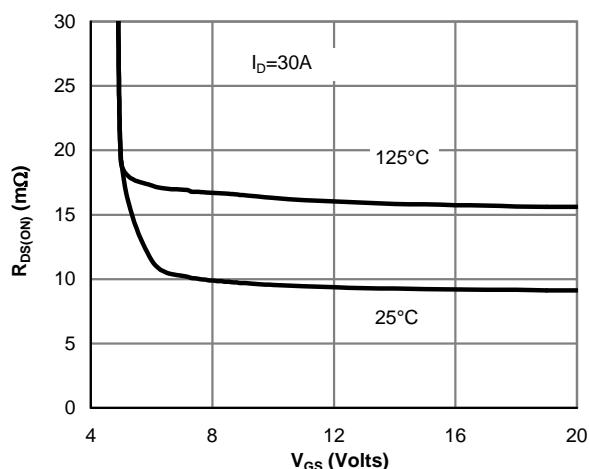


Figure 5: On-Resistance vs. Gate-Source Voltage

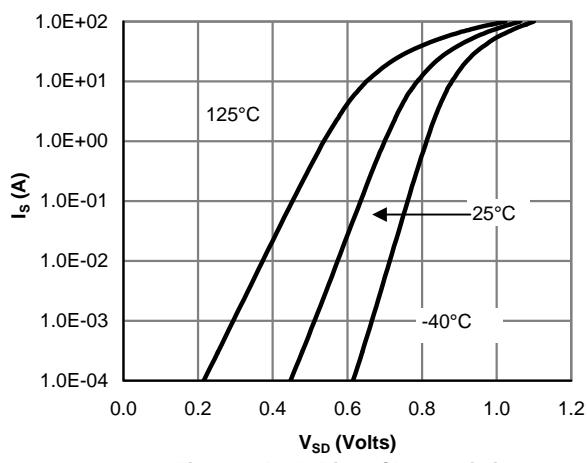


Figure 6: Body-Diode Characteristics

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

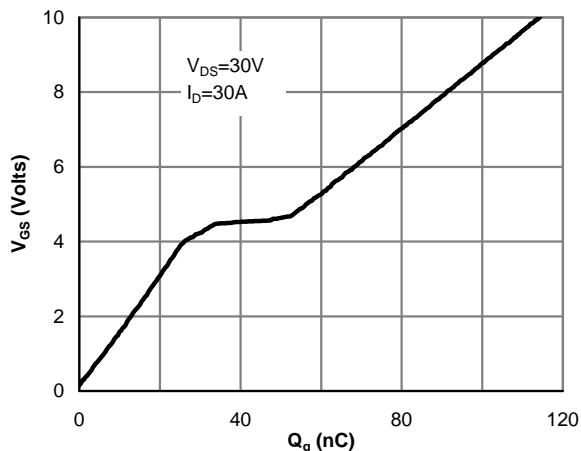


Figure 7: Gate-Charge Characteristics

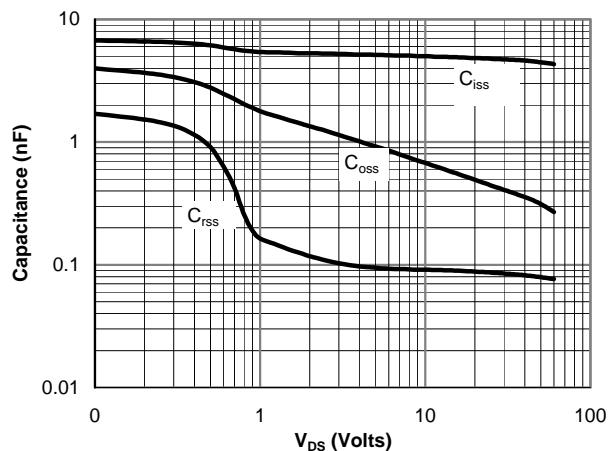


Figure 8: Capacitance Characteristics

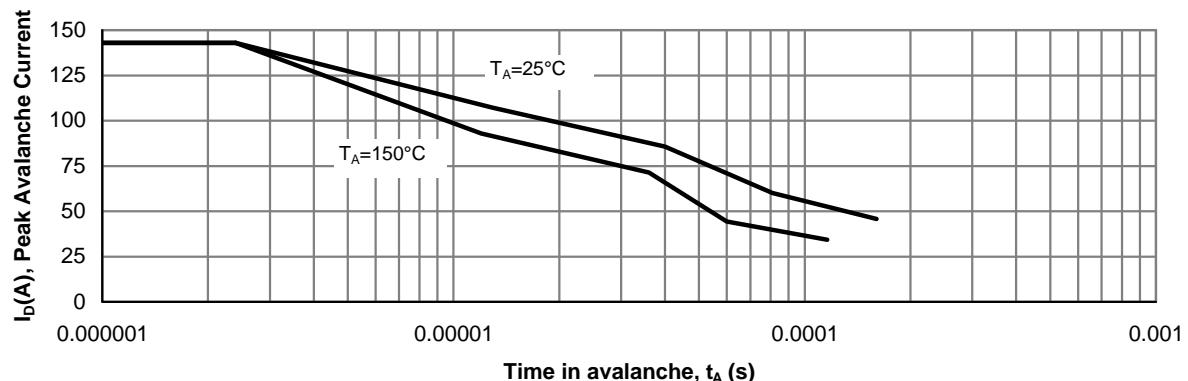


Figure 9: Single Pulse Avalanche capability

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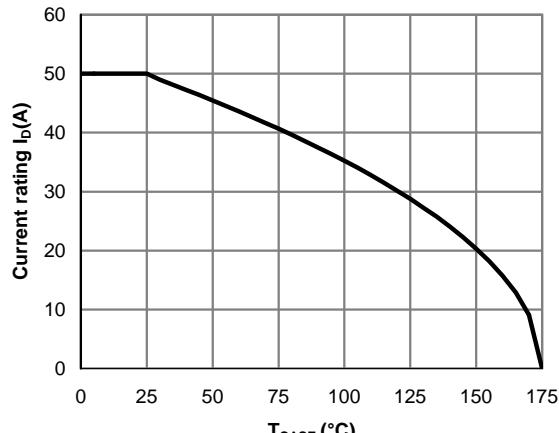
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 10: Current De-rating (Note B)

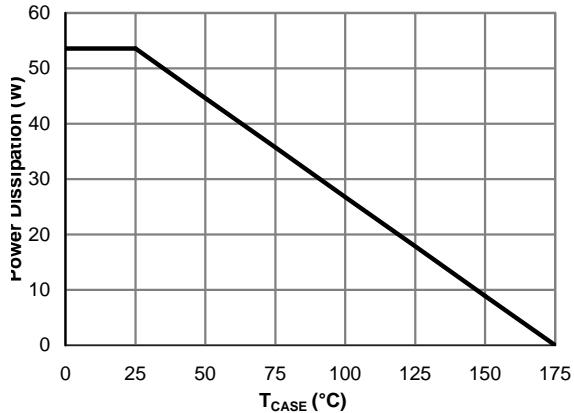


Figure 11: Power De-rating (Note B)

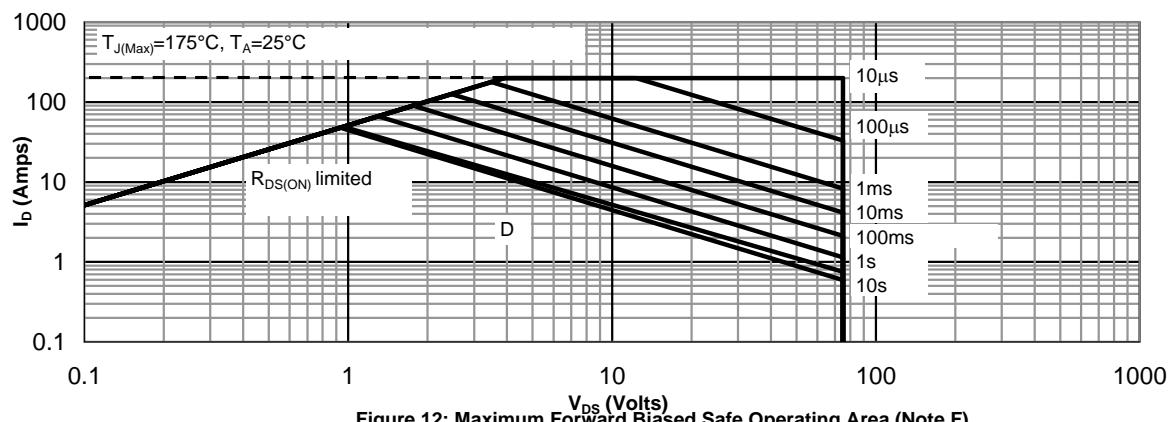


Figure 12: Maximum Forward Biased Safe Operating Area (Note F)

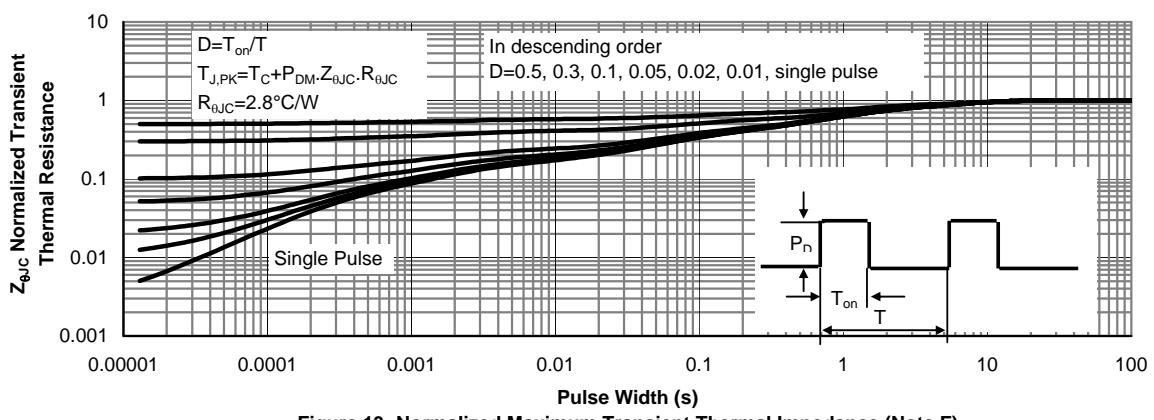


Figure 13: Normalized Maximum Transient Thermal Impedance (Note F)